

# Search Notes



Application/Control No.

09/714,317

Examiner

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Applicant(s)/Patent under Reexamination

TAKAKU ET AL.

Art Unit

2182

## SEARCHED

Class	Subclass	Date	Examiner
710	5-7, 15-18	9-5-03 4-1-04 4/5/05	CBS
710	29,31-33		CBS
710	46-50		CBS
710	58-61		CBS
709	220-223		CBS
709	230-237		CBS
711	163		CBS
713	201		CBS
340	825.24		CBS

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
710	61,46,17	6/22/2005	2
709	230	6/22/2005	2

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
PLUS	9-5-03 4-1-04 2-8-05	CBS
PALM FOR DOUBLE PATENTING	6-20-05	CBS
EAST (EPO, JPO, DERWENT, IBMTDB, USPGPUB, IDERWENT, USOCR)	9-5-03 4-1-04 4/5/05	CBS